



BSI Standards Publication

Measurement of quartz crystal unit parameters

Part 6: Measurement of drive level dependence (DLD)

National foreword

This British Standard is the UK implementation of EN IEC 60444-6:2021. It is identical to IEC 60444-6:2021. It supersedes BS EN 60444-6:2013, which will be withdrawn on 9 May 2022.

The UK participation in its preparation was entrusted to Technical Committee EPL/49, Piezoelectric devices for frequency control and selection.

A list of organizations represented on this committee can be obtained on request to its committee manager.

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Amendments/corrigenda issued since publication

Date	Text affected
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English Version

Measurement of quartz crystal unit parameters - Part 6:
Measurement of drive level dependence (DLD)
(IEC 60444-6:2021)

Mesure des paramètres des résonateurs à quartz - Partie 6:
Mesure de la dépendance du niveau d'excitation (DNE)
(IEC 60444-6:2021)

Messung von Schwingquarz-Parametern - Teil 6: Messung
der Belastungsabhängigkeit (DLD)
(IEC 60444-6:2021)

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

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European foreword

The text of document 49/1374/FDIS, future edition 3 of IEC 60444-6, prepared by IEC/TC 49 “Piezoelectric, dielectric and electrostatic devices and associated materials for frequency control, selection and detection” was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 60444-6:2021.

The following dates are fixed:

- latest date by which the document has to be implemented at national (dop) 2022-07-06 level by publication of an identical national standard or by endorsement
- latest date by which the national standards conflicting with the (dow) 2024-10-06 document have to be withdrawn

This document supersedes EN 60444-6:2013 and all of its amendments and corrigenda (if any).

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In the official version, for Bibliography, the following note has to be added for the standard indicated:

IEC 60444-1 NOTE Harmonized as EN 60444-1

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60444-5	-	Measurement of quartz crystal units parameters - Part 5: Methods for the determination of equivalent electrical parameters using automatic network analyser techniques and error correction	EN 60444-5	-
IEC 60444-8	-	Measurement of quartz crystal unit parameters - Part 8: Test fixture for surface mounted quartz crystal units	EN 60444-8	-

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

MEASUREMENT OF QUARTZ CRYSTAL UNIT PARAMETERS –**Part 6: Measurement of drive level dependence (DLD)****FOREWORD**

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IEC 60444-6 has been prepared by IEC technical committee 49: Piezoelectric, dielectric and electrostatic devices and associated materials for frequency control, selection and detection. It is an International Standard.

This third edition cancels and replaces the second edition published in 2013. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) some equations have been removed and corrected;
- b) it has been specified in the note of the Scope that the measurement methods specified in this document are not only applicable to AT-cut but also to other crystal cuts and vibration modes.